

Assessment of photodetection performance of analog and digital SiPMs when exposed to cold neutrons

June 14, 2018 | Daniel Durini^{1,2*}, Shashank Kumar¹, David Arutinov¹, Carsten Degenhardt¹, Stefan van Waasen^{1,3}

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Advancement of Silicon Photomultipliers

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- Conclusions and Outlook

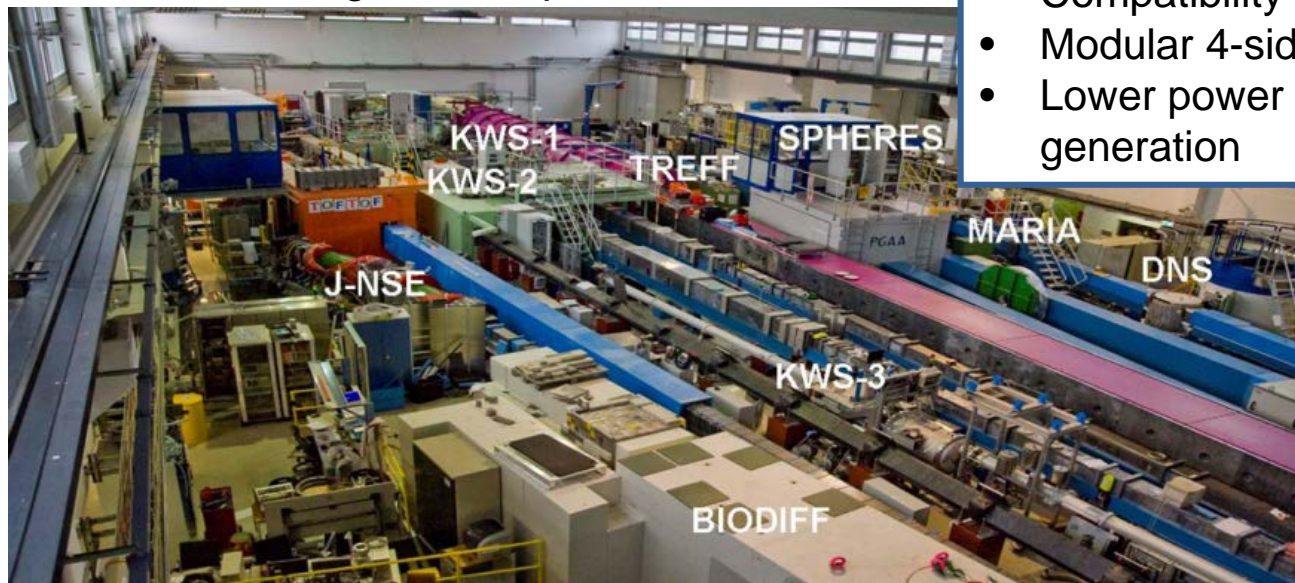
Motivation

Small-angle neutron scattering (SANS):

- Soft matter investigations
- No electric charge → nuclear reactions
- Neutron magnetic moment → investigation of magnetic properties of matter
- Thermal and cold neutrons (1 – 25 meV) deposit only minimum amounts of energy into the investigated sample

We need:

- Higher spatial resolutions ($< 1 \text{ mm}^2$)
- Higher count rates (to match any future neutron source)
- Compatibility with magnetic fields
- Modular 4-side tileable detectors
- Lower power consumption and heat generation

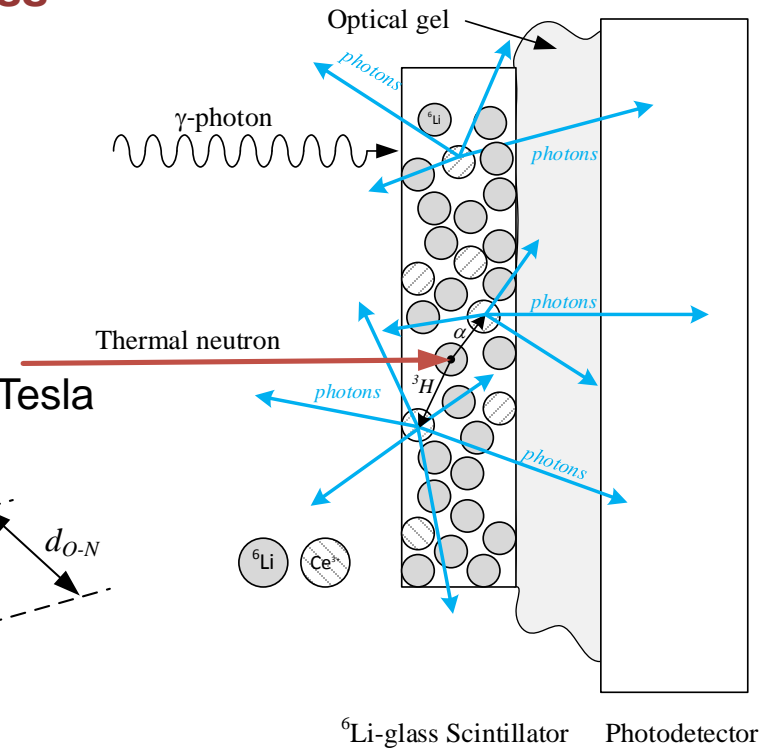
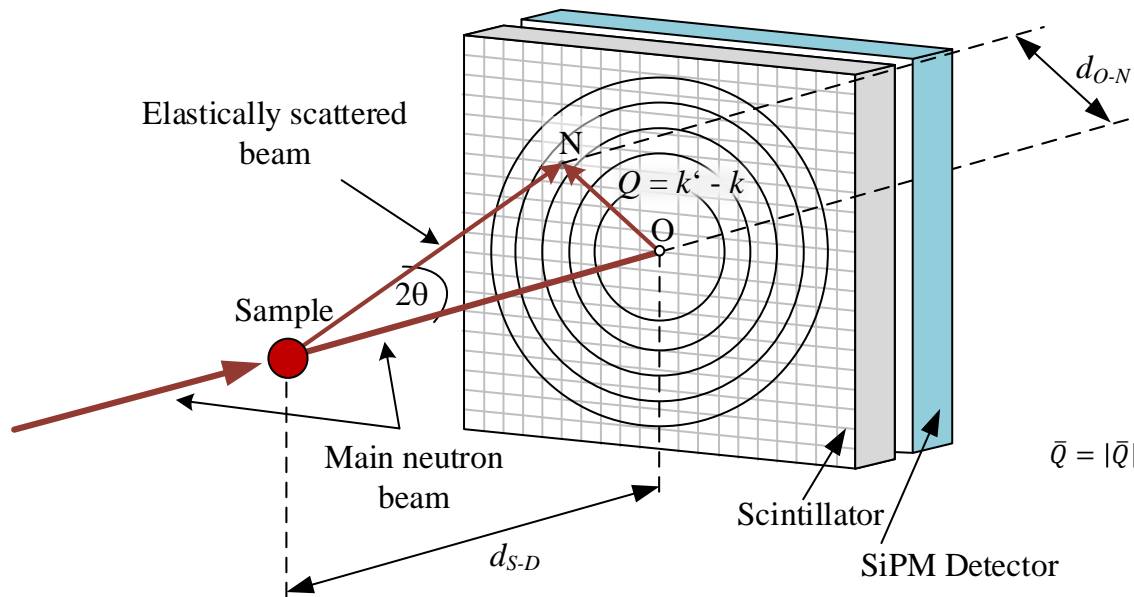


Experimental hall at MLZ (*Heinz Maier Leibnitz Zentrum*) Garching, Munich

We propose...

SANS solid-state pixelated and modular scintillation detectors using Ce-doped ⁶Li-glass scintillator and an underlying array of SiPM photodetectors:

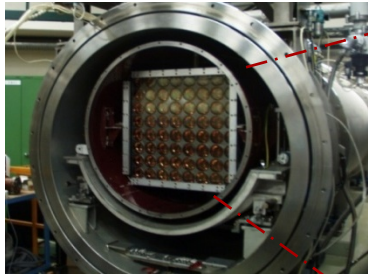
- Near single photon counting → high η_n
- Low bias voltages (20-70 V)
- Acceptable space resolution (< 1 mm sq.)
- Neutron counting rates ~ 100 Mcps/m²
- Insensitivity to magnetic fields up to several Tesla



$$\bar{Q} = |\bar{Q}| = \sqrt{k^2 + k'^2 - 2kk' \cos 2\theta} \quad \text{yields} \quad |\bar{Q}| = \frac{4\pi}{\lambda_n} \sin \theta$$

Typical operating conditions for SANS experiments

PMT based Anger-camera scintillation detector installed at the KWS-1 instrument of the MLZ in Garching, Germany. The detector has an active area of 60 x 60 cm²:

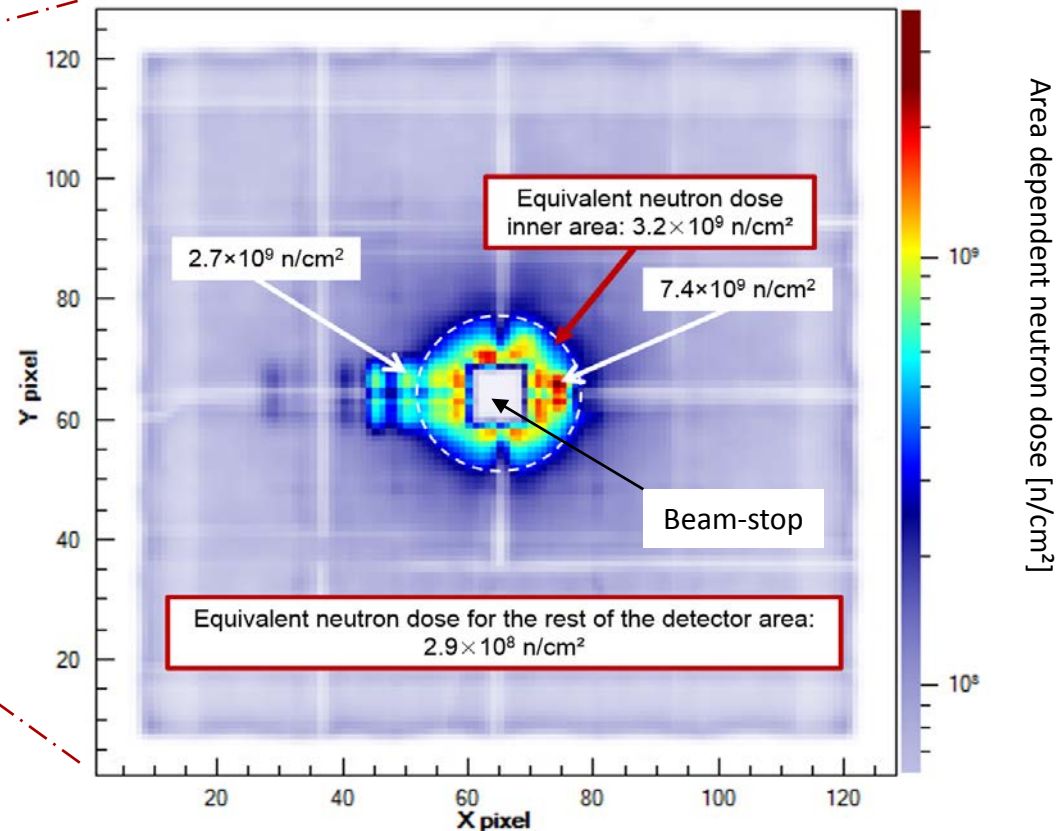


Scale-up factor of 7.9 used for the maximum amount of neutrons expected at the instrument in the future.

Technical data of the KWS-1 instrument:

- $Q = 0.0007 - 0.5 \text{ \AA}^{-1}$
- Maximal neutron flux: $1.5 \times 10^8 \text{ n}\cdot\text{cm}^{-2}\cdot\text{s}^{-1}$
- Neutron velocity selector (chopper, FWHM 10%): $\lambda_n = 4.5 \text{ \AA} - 12 \text{ \AA}$; typically

$$\lambda_n = 5 \text{ \AA} \rightarrow E_n = 3.27 \text{ meV}$$



Graphical presentation of the amount of neutrons detected during 240 days (between August 2014 and October 2015) across all kinds of experiments and setups available at the instrument.

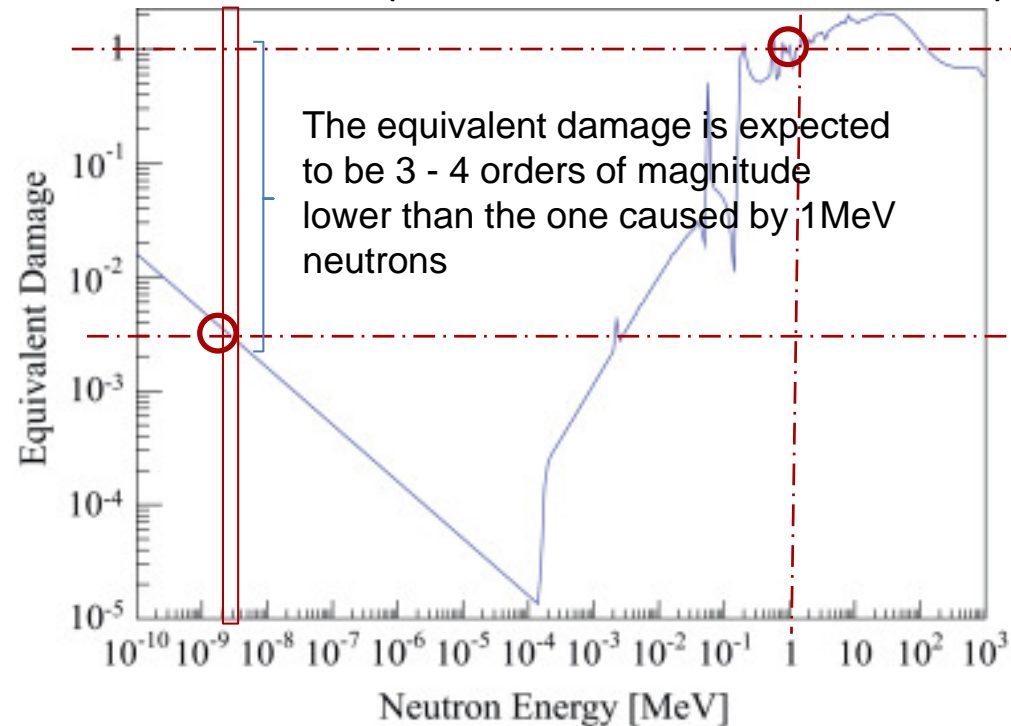
Main concern:

Radiation Hardness of SiPMs

Radiation damage for SiPMs:

- Ionizing damage (mainly due to high-energy gamma photons) 🤔
- Displacement damage (DD): 25 eV for a Si atom to be displaced → 175 keV neutrons for generation of *Frenkel* pairs (silicon interstitial and vacancy) to be produced 🤔
- Single event effects (SEE): range of effects caused by ionization from a single, high energy particle 😊

Effective damage to Silicon detectors relative to 1 MeV neutron (irradiated with white neutrons):

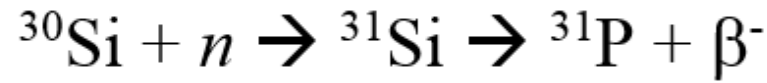


Source: Qiang et al. "Radiation hardness tests of SiPMs for the JLab Hall D Barrel calorimeter", NIMA 698 (2013) 234–241

Main concern:

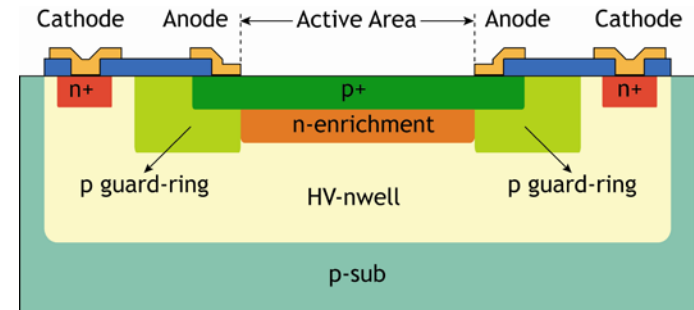
Radiation Hardness of SiPMs

Nuclear transmutation processes initiated by **thermal neutron (n) capture**:



Damage introduced into silicon by thermal/cold neutrons is primarily **in form of point defects**, approximately **2-5 defects per absorbed neutron** remaining at room temperature.

$$|I_{\text{dark}}| = \alpha_p \left\{ qA_n \left(\frac{n_i^2}{N_D} \sqrt{\frac{D_p}{\tau_{r-p}}} + N_{\text{def}} W_{\text{SCR}} \sigma_n c_n T^2 e^{\left(\frac{E_c - E_T}{k_B T} \right)} \right) \right\}$$



Typical SPAD structure

Source: Durini et al., "CMOS Technology for SPAD / SiPM. Results from the MiSPIA Project", 7th IMS Workshop, 2014

Increase in the dark signal of the SiPMs!

We investigated the dark signal and PDE performances of 3 SiPM technologies under irradiation with cold neutrons.

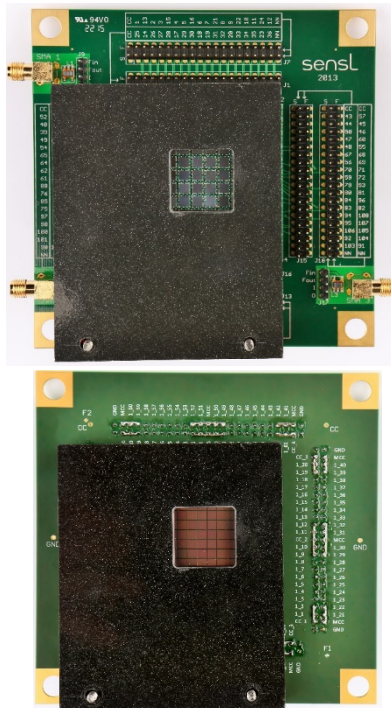
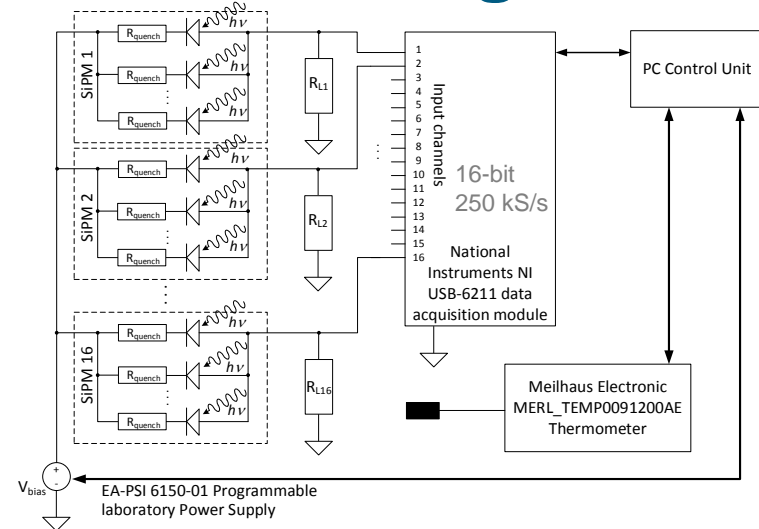
For dark signal deterioration assessment, we measured it during irradiation with cold neutrons both, with and without a scintillator material covering the photodetector arrays.

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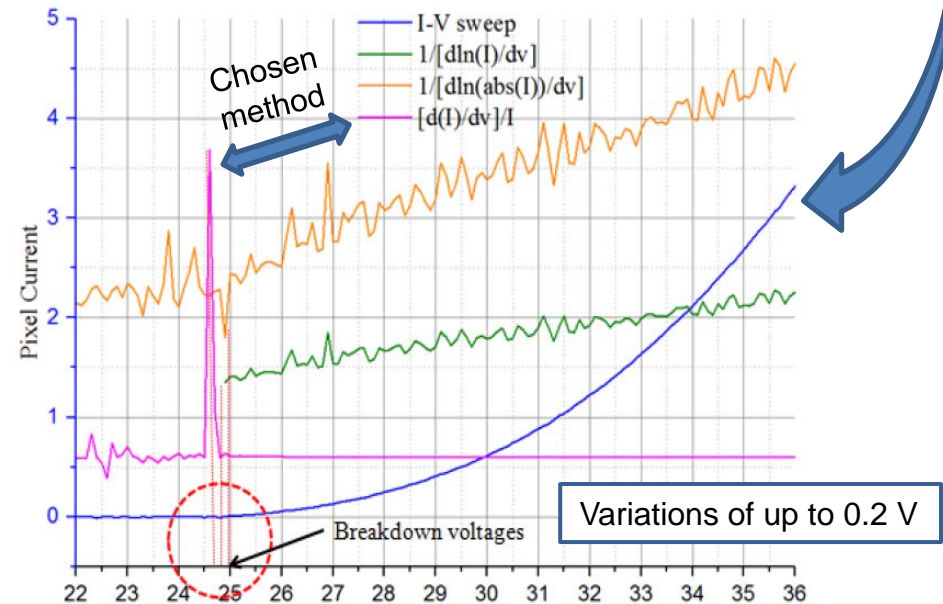
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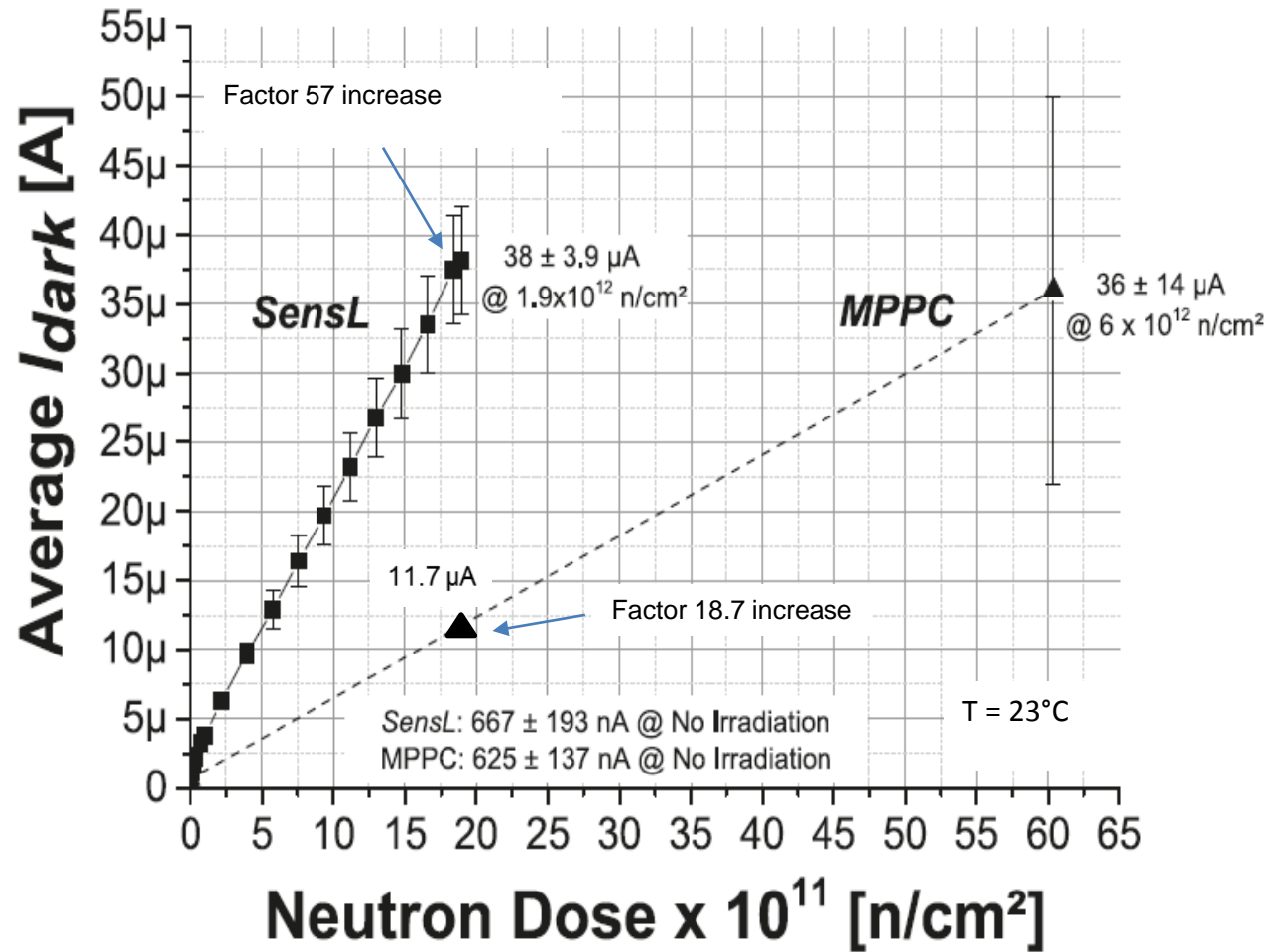
Radiation Hardness of SiPMs: Dark Signal

Investigated SiPM technologies →	SensL Series-C ArrayC-30035-144P-PCB	Hamamatsu 8 × 8 MPPC array S12642-0808PB-50
Array format	12 × 12	8 × 8
Pitch of each individual detector, mm	4.2	3.2
Array package size (4-side tileable), mm ²	50.2 × 50.2	22.4 × 25.8
Active area of each individual sensor (pixel), mm ²	3 × 3	3 × 3
Microcell size, μm	35	50
No. of micro-cells	4774	3584
Micro-cell fill-factor, %	64	62
Detector fill-factor, %	51	87.9



SensL Series-C I-V curve and V_{br} analysis

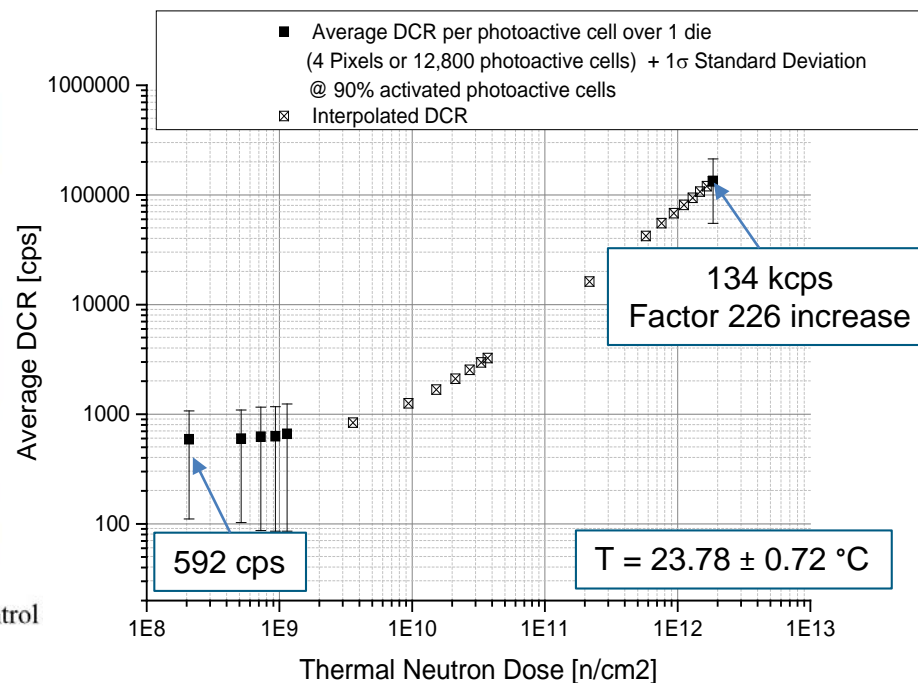
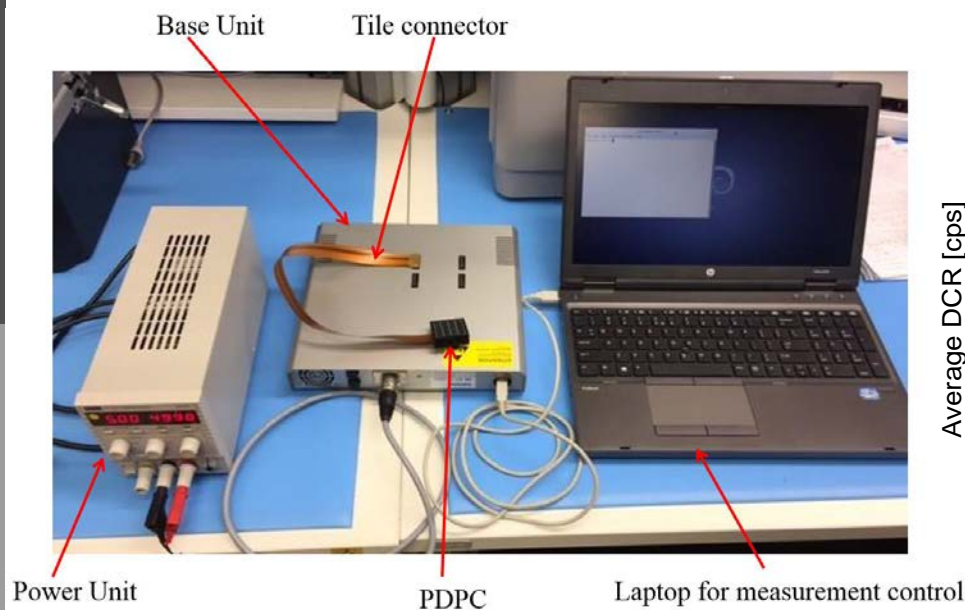
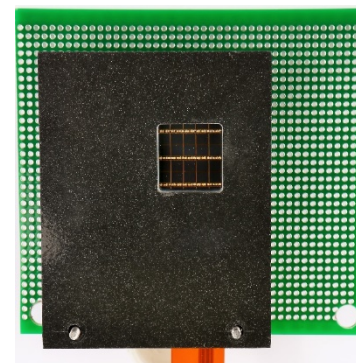


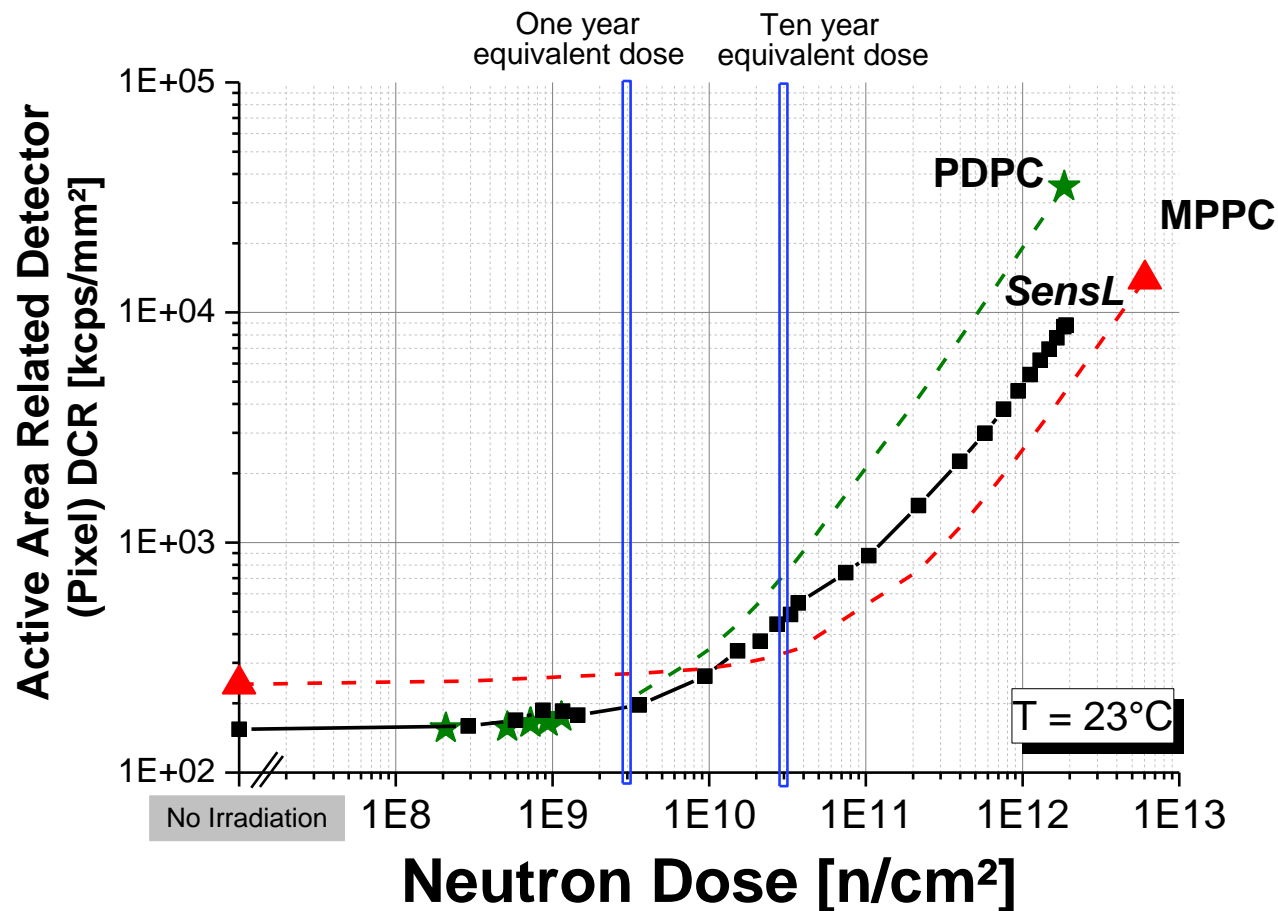


Source: Durini et al., NIMA 835 (2016) 99–109

Radiation Hardness of SiPMs: Dark Signal

<i>Philips DPC3200-22-44</i>		
Array format	8 × 8	SiPM
Pitch of each individual SiPM detector	4.0	mm
Array package size (4-side tillable)	32.6 × 32.6	mm ²
Active area of each individual sensor	3.2 × 3.8	mm ²
Microcell size	59.4 × 64	μm ²
No. of micro-cells	3200	1
Micro-cell fill-factor	74	%

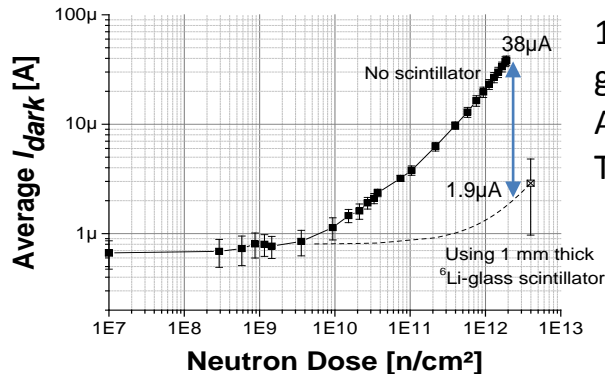




Normalizing the aSiPM dark currents:

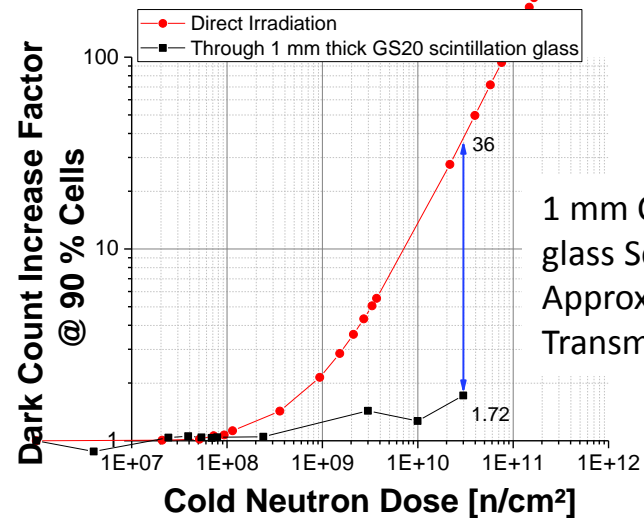
$$DCR = \frac{I_{dark}}{q \cdot G \cdot A_{active}} \left(\frac{100 - XT - AP}{100} \right)$$

SensL SiPM detectors with $3 \times 3 \text{ mm}^2$ photoactive areas, biased at $(V_{br}+2.5) \text{ V}$ @ $T = 23^\circ \text{ C}$:



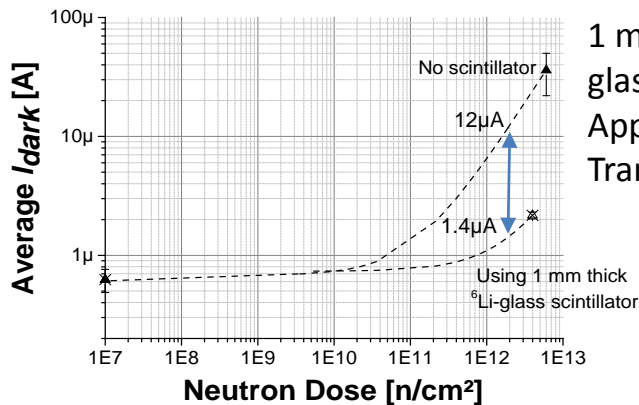
1 mm Ce-doped ^6Li -glass Scintillator
Approx.
Transmission: $\sim 5\%$

Philips DPC detectors with $4 \times 4 \text{ mm}^2$ photoactive areas, biased at $(V_{br}+3) \text{ V}$ @ $T = 23^\circ \text{ C}$:



1 mm Ce-doped ^6Li -glass Scintillator
Approx.
Transmission: $\sim 5\%$

Hamamatsu MPPC $3 \times 3 \text{ mm}^2$ photoactive area detectors, biased at $(V_{br}+2.4) \text{ V}$ @ $T = 23^\circ \text{ C}$



1 mm Ce-doped ^6Li -glass Scintillator
Approx.
Transmission: $\sim 12\%$

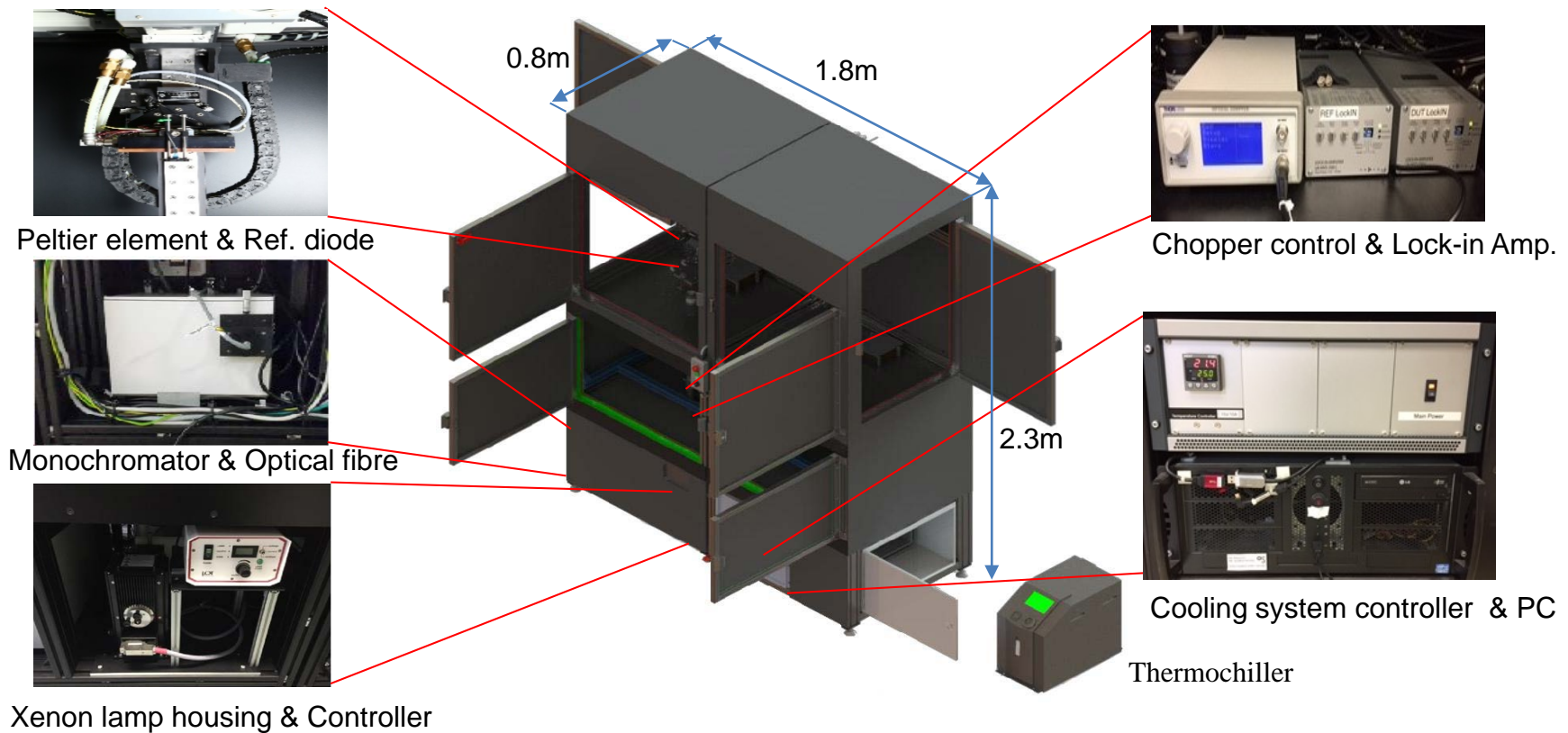
Assumption for future work: approx. 10 % of impinging neutrons get absorbed in the scintillator.

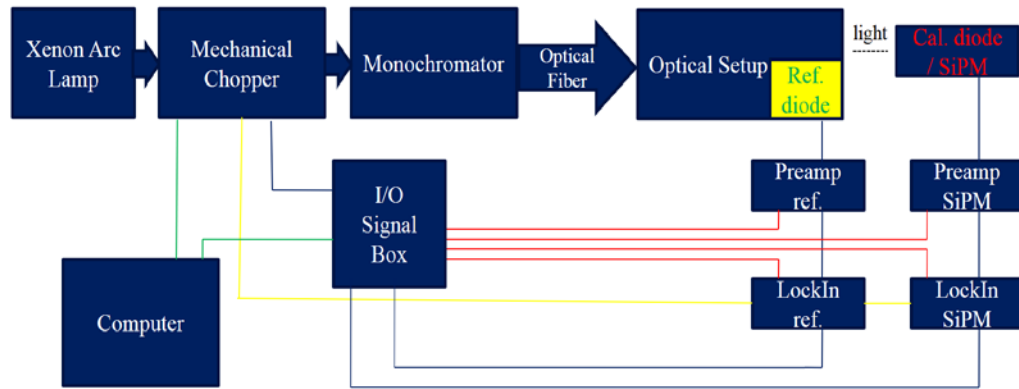
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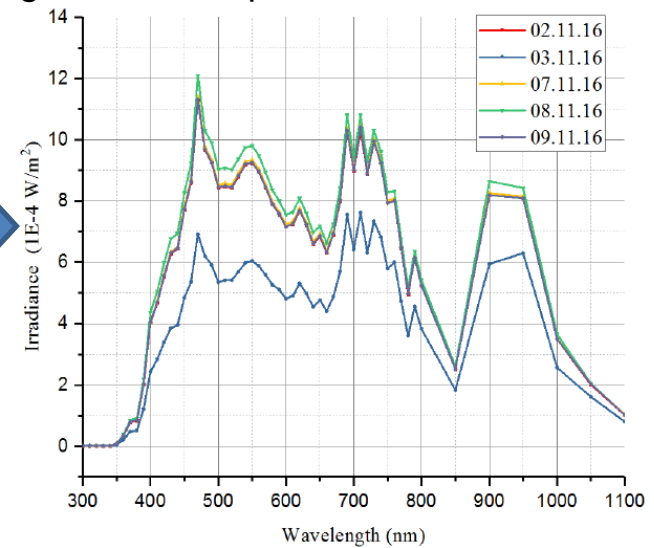
Radiation Hardness of SiPMs: PDE issues

Opto Measurement System Setup



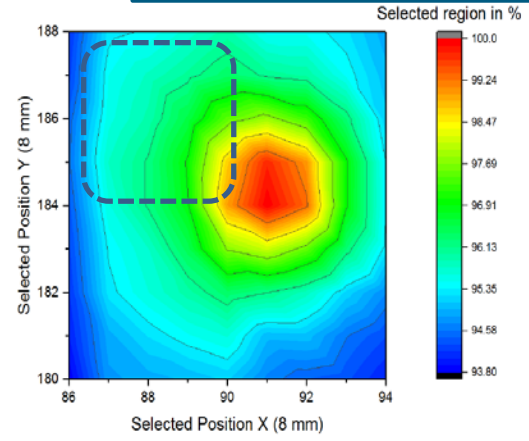


Example of repeated irradiance measurements using a reference photodiode:



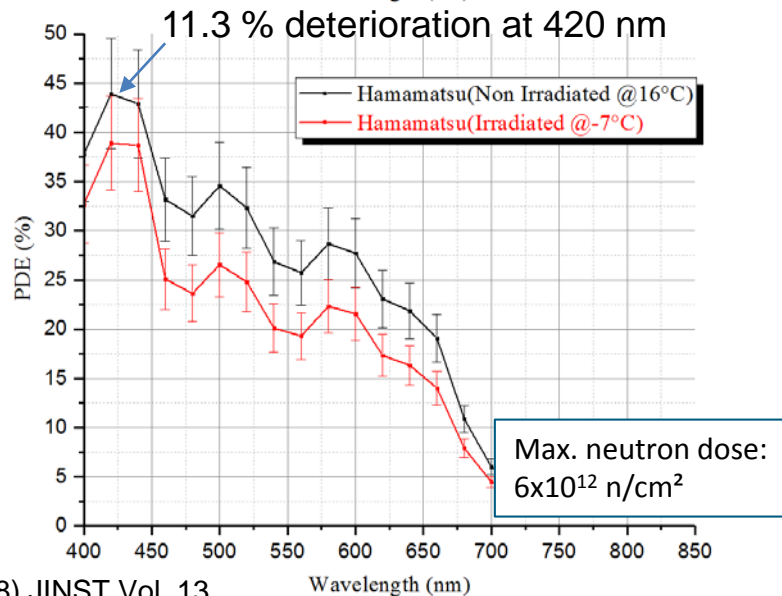
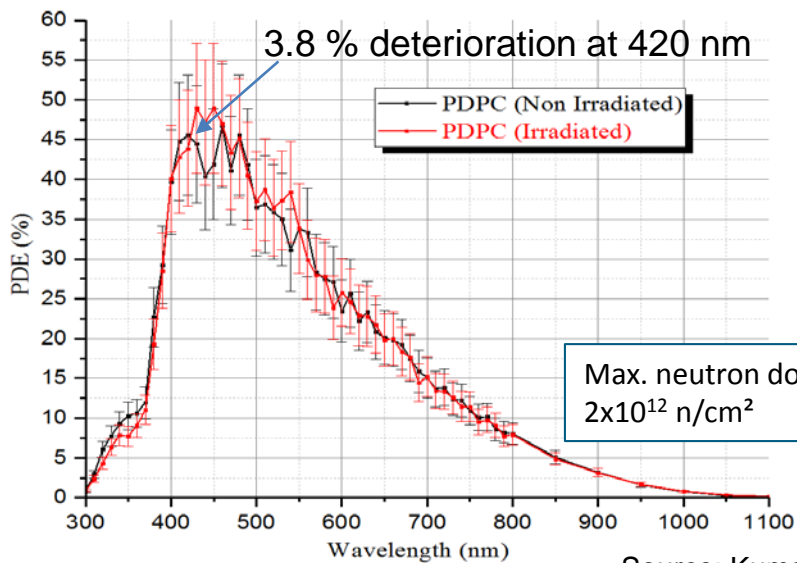
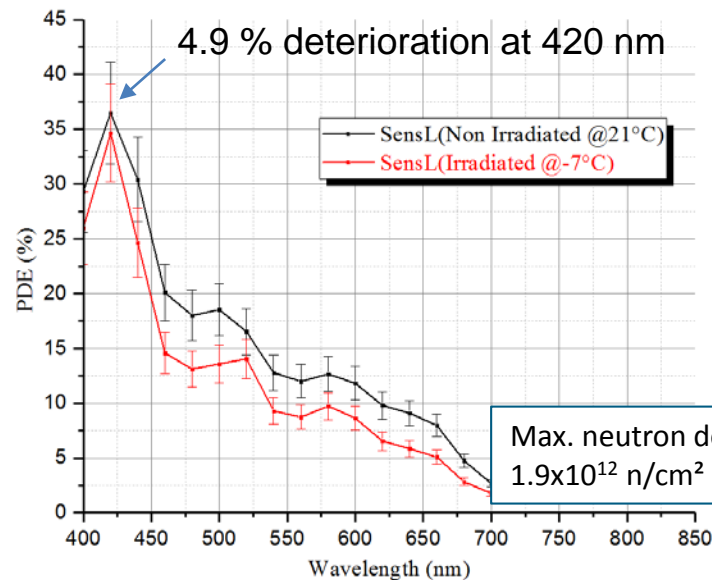
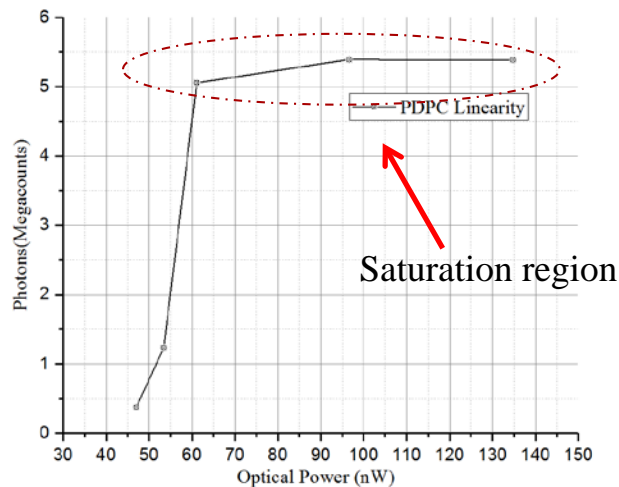
Resulting system uncertainty (including the uncertainty of the ref. PD): 16.6 %

Illumination spot uniformity (8 x 8 mm²):



Radiation Hardness of SiPMs: PDE issues

Optimizing the measurement system for “single-photon counting” devices is never easy...



Source: Kumar et al. (2018) JINST Vol. 13

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Conclusions and Outlook:

- **SiPM technology is viable for solid-state pixelated scintillation detectors to be used in SANS applications** having over 10-year life-times
- *Hamamatsu* MPPCs showed higher radiation hardness than *SensL Series-C* and *Philips DPC* → **all three technologies remained within goal specifications**
- An annealing effect at room temperature was observed and will be investigated further (also using active heating or illumination)
- The relative **deterioration in PDE** ($\lambda = 420$ nm) after irradiation with 5 Å cold neutrons is proportional to the increase in the DCR → **remained within goal specifications**
- **We chose the Philips DPC technology** and developed and characterized the first SANS PDPC based **solid-state scintillation detector demonstrator** yielding:
 - Count-rate (linearity > 90%): **>110 Mcps for 60 x 60 cm²**
 - Neutron Detection Efficiency: 75 ± 5 % @ 5 Å
 - Spatial resolution: **$\geq 1 \times 1$ mm² for monolithic scintillator glass**
 - A prototype detector of 13 x 13 cm² is currently under development

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Thank you very much for
your attention!

...any questions?